



Degradation Study of SOC Stacks with Impedance Spectroscopy

Yulin Yan

Energie & Umwelt / Energy & Environment

Band / Volume 441

ISBN 978-3-95806-367-9

Forschungszentrum Jülich GmbH
Institut für Energie- und Klimaforschung
Elektrochemische Verfahrenstechnik (IEK-3)

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Schriften des Forschungszentrums Jülich
Reihe Energie & Umwelt / Energy & Environment

Band / Volume 441

ISSN 1866-1793

ISBN 978-3-95806-367-9

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